

## Lab 2

### Problem: VLSI chip testing

Professor Diogenes has  $n$  supposedly identical VLSI chips that in principle are capable of testing each other. The professor's test jig accommodates two chips at a time. When the jig is loaded, each chip tests the other and reports whether it is good or bad. A good chip always reports accurately whether the other chip is good or bad, but the answer of a bad chip cannot be trusted. Thus, the four possible outcomes of a test are as follows:

Chip A says	Chip B says	Conclusion
B is good	A is good	both are good, or both are bad
B is good	A is bad	at least one is bad
B is bad	A is good	at least one is bad
B is bad	A is bad	at least one is bad

- Show that if more than  $n/2$  chips are bad, the professor cannot necessarily determine which chips are good using any strategy based on this kind of pairwise test. Assume that the bad chips can conspire to fool the professor.
- Consider the problem of finding a single good chip from among  $n$  chips, assuming the more than  $n/2$  of the chips are good. Show that  $\lfloor n/2 \rfloor$  pairwise tests are sufficient to reduce the problem to one of nearly half the size.
- Show that the good chips can be identified with  $\Theta(n)$  pairwise tests, assuming that more than  $n/2$  of the chips are goods. Give and solve the recurrence that describes the number of tests.